

<b>Notic of References Cited</b>	Application/Control No.	Applicant(s)/Patent Under Reexamination	
	10/089,488	ARNONE ET AL.	
Examiner John D. Lee	<i>John D. Lee</i>	Art Unit 2874	Page 1 of 1

**U.S. PATENT DOCUMENTS**

*	Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
A	US-4,943,145	07-1990	Miyata, Seizo	359/244
B	US-5,379,311	01-1995	McFarlane et al.	372/41
C	US-			
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E	US-			
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H	US-			
I	US-			
J	US-			
K	US-			
L	US-			
M	US-			

**FOREIGN PATENT DOCUMENTS**

*	Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
N					
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**NON-PATENT DOCUMENTS**

*	Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages
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